

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/686,052	AHNE ET AL.	
Examiner	Art Unit	
Quan Tra	2816	

SEARCHED						
Subclass	Date	Examiner				

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
limited search 327/525, 526; 365/225.7	12/12/2006	QT		